

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/516,517	ENJO ET AL.		
Examiner	Art Unit		
Nirmal S. Basi	1646		

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
sequence search	6/13/2007	STIC